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Michel Renovell, Seiji Kajihara, Ibrahim Ai-Bahadly, Serge Demidenko

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Proceedings

The First IEEE International Workshop on
Electronic Design, Test and Applications



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Proceedings

The First IEEE International Workshop on
Electronic Design, Test and Applications


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Edited by

M. Renovell, S. Kajihara, I. Al-Bahadly and S. Demidenko

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